Notice of References Cited

Application/Control No. 10/659,468	Reexamination	Applicant(s)/Patent Under Reexamination SHAKUTO ET AL.	
Examiner	Art Unit		
Susan S. Lee	2852	Page 1 of 1	

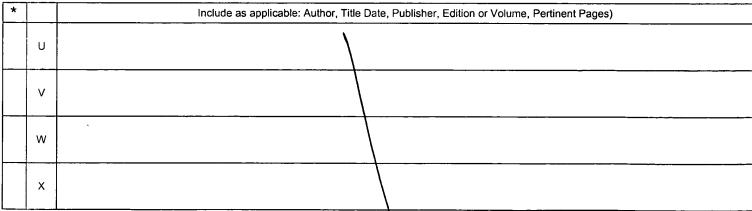
U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,801,747 B2	10-2004	Ogara et al.	399/350
	В	US-6,694,122 B2	02-2004	Muto et al.	399/350
	С	US-6,836,638 B2	12-2004	Muto et al.	399/350
	D	US-4,875,070	10-1989	Hattori, Yutaka	399/350
	E	US-2003/0031488 A1	02-2003	Kunishi et al.	399/350
	F	US-4,111,545	09-1978	Meltzer, David W.	399/351
	G	US-4,982,240	01-1991	Nakano, Masaru	399/350
	Н	US-6,203,962 B1	03-2001	Itami et al.	399/350
	ı	US-6,128,461 A	10-2000	Yoshikawa, Tadanobu	399/350
	J	US-2003/0063928 A1	04-2003	Matsuguma, Minoru	/
	К	US-6,463,254	10-2002	Maul et al.	399/350
	L	US-			·
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
* .	Ν	JP 11174922 A	07-1999	Japan	YOSHIKAWA, TADANOBU	G03G 21/10
	0	JP 07337042 A	12-1995	Japan	MURAMATSU, KENICHI	H02N 02/00
	Ρ	JP 09034249 A	02-1997	Japan	ICHIDA et al.	G03G 15/08
	ď	JP 2002268490 A	09-2002	Japan	NAKAMURA et al.	G03G 21/10
	R	JP 2001066963 A	03-2001	Japan	ITAMI et al.	G03G 21/10
	s					
	Т					

NON-PATENT DOCUMENTS



*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.